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NATIONAL STANDARD OF THE

PEOPLE'S REPUBLIC OF CHINA

GB/T 15651.11-2026

Semiconductor devices-Part 5-11: Optoelectronic devices-Light emitting diodes-Test method of radiative and nonradiative currents of light emitting diodes

半导体器件 第5-11部分：光电子器件 发光二极管 辐射和非辐射电流的测试方法

(English Translation)

Issued on: October 30, 2026 **Implemented on: May 1, 2027**

Issued by: State Administration for Market Regulation;
Standardization Administration of China

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https://chinastandards.org/standards/gb-t-15651-11-2026

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1 Foreword

GB/T 15651.11-2026 was issued by State Administration for Market Regulation; Standardization Administration of China on 30 October 2026 and takes effect on 1 May 2027.

It is one of 13 parts of the GB/T 15651 series.

The GB/T prefix marks a recommended standard. It is not law in itself: it becomes binding when a contract names it, when a regulation or a mandatory standard refers to it, or when a producer declares conformity with it.

2 Scope Preview

GB/T 15651.11-2026 carries no ICS number and no Chinese Standard Classification code.

This catalogue holds 76,457 other GB/T standards.

Of the 47,415 GB/T standards that do carry an ICS number, 3,437 (7%) fall under ICS 77, in the field of metallurgy.

3 About this standard

Issued by: State Administration for Market Regulation; Standardization Administration of China

4 Related standards

Other parts of this standard:

GB/T 15651-1995 - Semiconductor devices--Discrete devices and integrated circuits. Part 5: Optoelectronic devices

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GB/T 15651.2-2003 - Discrete semiconductor devices and integrated circuits -- Part 5-2: Optoelectronic devices Essential ratings and characteristics

GB/T 15651.3-2003 - Discrete semiconductor devices and integrated circuits -- Part 5-3: Optoelectronic devices Measuring methods

GB/T 15651.4-2017 - Semiconductor devices - Part 5-4: Optoelectronic devices - Semiconductor lasers

GB/T 15651.4-2026 - Semiconductor devices - Part 5-4: Optoelectronic devices - Semiconductor lasers

GB/T 15651.5-2024 - Semiconductor devices - Part 5-5: Optoelectronic devices - Photocouplers

GB/T 15651.6-2023 - Semiconductor devices - Part 5-6: Optoelectronic devices - Light emitting diodes

GB/T 15651.7-2024 - Semiconductor devices - Part 5-7: Optoelectronic devices - Photodiodes and phototransistors

GB/T 15651.8-2026 - Semiconductor devices-Part 5-8: Optoelectronic devices-Light emitting diodes-Test method of optoelectronic efficiencies of light emitting diodes

GB/T 15651.9-2026 - Semiconductor devices-Part 5-9: Optoelectronic devices-Light emitting diodes-Test method of the internal quantum efficiency based on the temperature-dependent electroluminescence

GB/T 15651.10-2026 - Semiconductor devices-Part 5-10: Optoelectronic devices-Light emitting diodes-Test method of the internal quantum efficiency based on the room-temperature reference point

GB/T 15651.13-2026 - Semiconductor devices - Part 5-13: Optoelectronic devices - Hydrogen sulphide corrosion test for LED packages

5 Classification and status

Prefix GB/T: recommended standard.

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